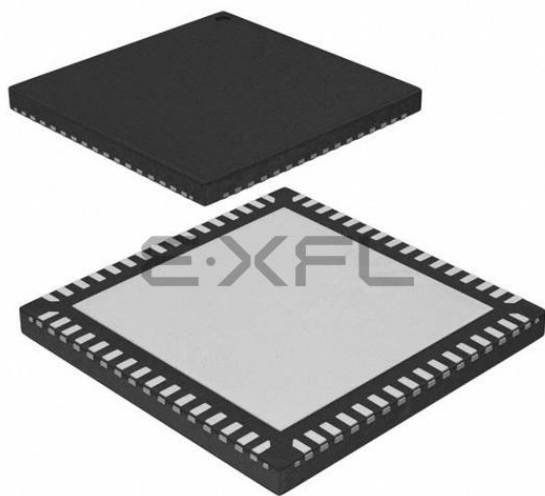




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Details

Product Status	Discontinued at Digi-Key
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I ² S, POR, PWM, WDT
Number of I/O	56
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 12bit SAR; D/A 12bit
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TJ)
Mounting Type	Surface Mount
Package / Case	64-VFQFN Exposed Pad
Supplier Device Package	64-QFN (9x9)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32tg11b140f64im64-a

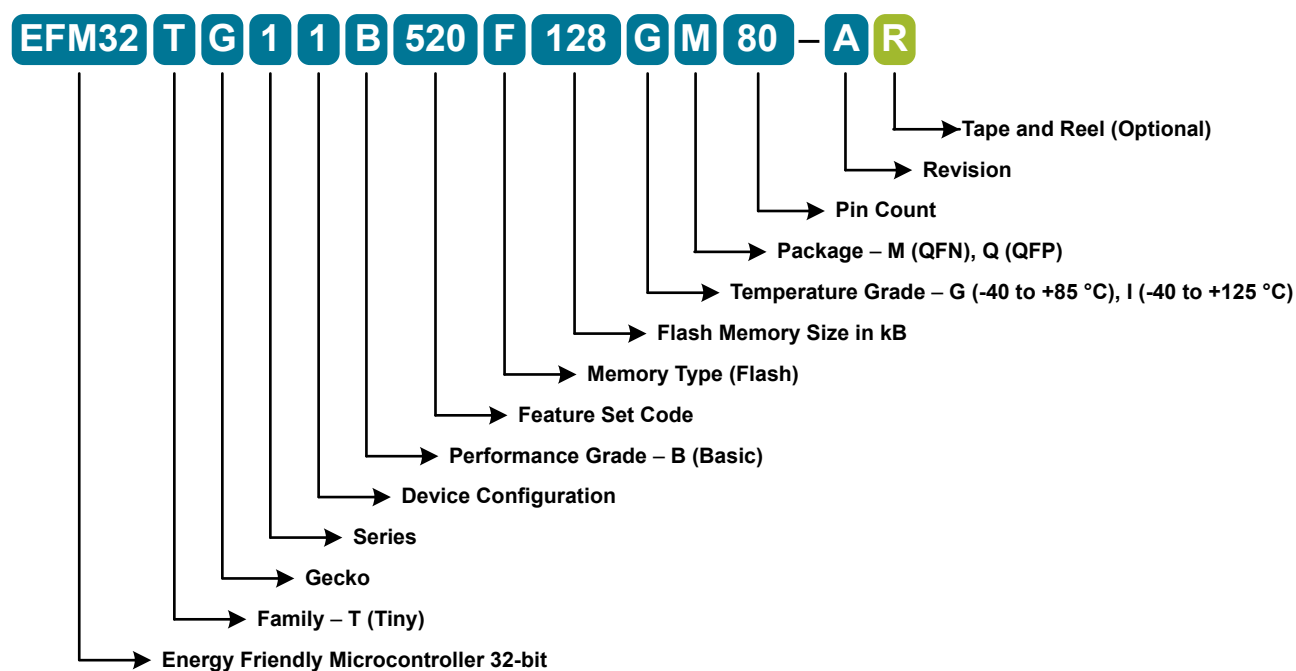


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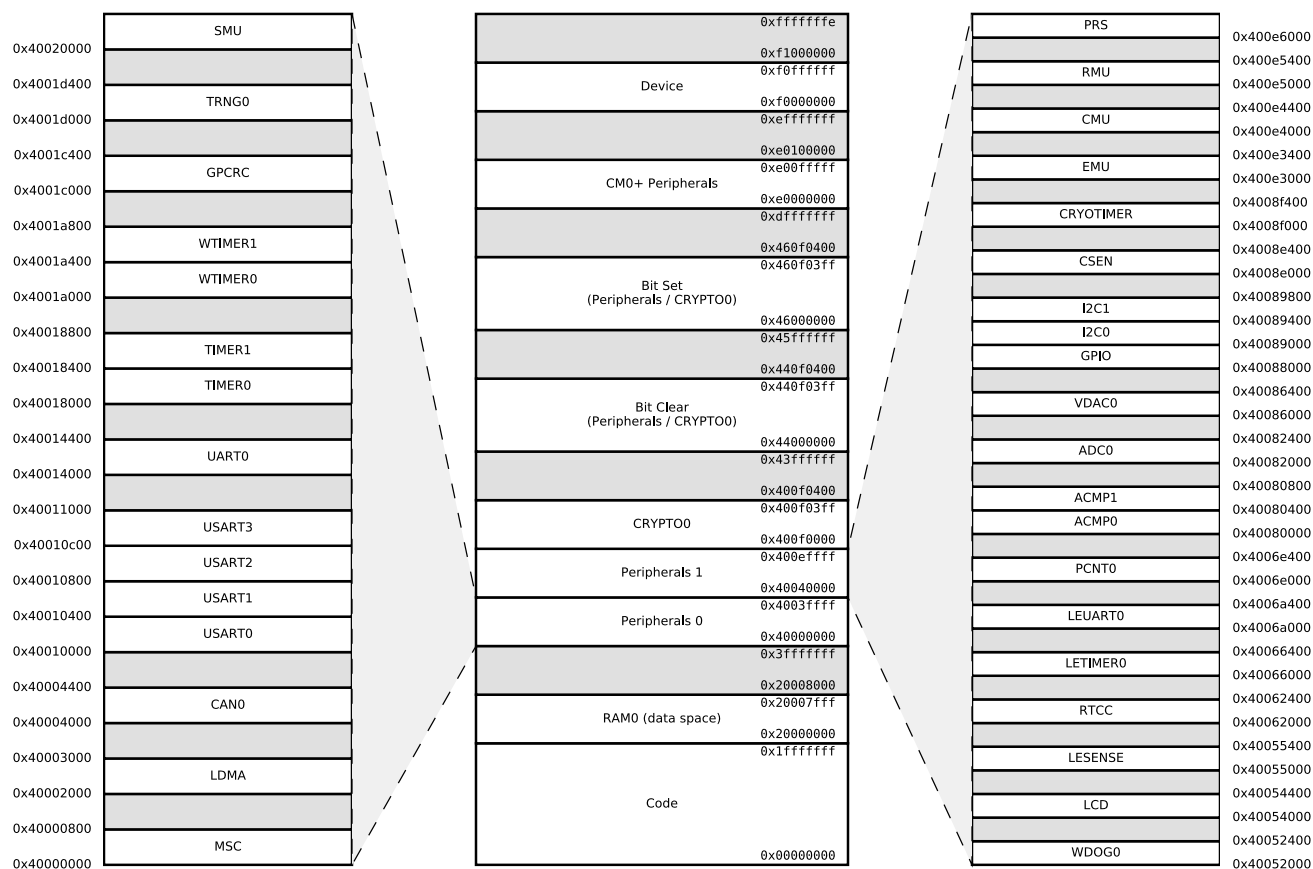


Figure 3.3. EFM32TG11 Memory Map — Peripherals

3.12 Configuration Summary

The features of the EFM32TG11 are a subset of the feature set described in the device reference manual. The table below describes device specific implementation of the features. Remaining modules support full configuration.

Table 3.2. Configuration Summary

Module	Configuration	Pin Connections
USART0	IrDA, SmartCard	US0_TX, US0_RX, US0_CLK, US0_CS
USART1	I ² S, SmartCard	US1_TX, US1_RX, US1_CLK, US1_CS
USART2	IrDA, SmartCard, High-Speed	US2_TX, US2_RX, US2_CLK, US2_CS
USART3	I ² S, SmartCard	US3_TX, US3_RX, US3_CLK, US3_CS
TIMER0	with DTI	TIM0_CC[2:0], TIM0_CDTI[2:0]
TIMER1	-	TIM1_CC[3:0]
WTIMER0	with DTI	WTIM0_CC[2:0], WTIM0_CDTI[2:0]
WTIMER1	-	WTIM1_CC[3:0]

4.1.6 Current Consumption

4.1.6.1 Current Consumption 3.3 V without DC-DC Converter

Unless otherwise indicated, typical conditions are: VREGVDD = AVDD = DVDD = 3.3 V. T = 25 °C. DCDC is off. Minimum and maximum values in this table represent the worst conditions across supply voltage and process variation at T = 25 °C.

Table 4.6. Current Consumption 3.3 V without DC-DC Converter

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Current consumption in EM0 mode with all peripherals disabled	I _{ACTIVE}	48 MHz crystal, CPU running while loop from flash	—	45	—	μA/MHz
		48 MHz HFRCO, CPU running while loop from flash	—	44	TBD	μA/MHz
		48 MHz HFRCO, CPU running Prime from flash	—	57	—	μA/MHz
		48 MHz HFRCO, CPU running CoreMark loop from flash	—	71	—	μA/MHz
		32 MHz HFRCO, CPU running while loop from flash	—	45	—	μA/MHz
		26 MHz HFRCO, CPU running while loop from flash	—	46	TBD	μA/MHz
		16 MHz HFRCO, CPU running while loop from flash	—	50	—	μA/MHz
		1 MHz HFRCO, CPU running while loop from flash	—	161	TBD	μA/MHz
Current consumption in EM0 mode with all peripherals disabled and voltage scaling enabled	I _{ACTIVE_VS}	19 MHz HFRCO, CPU running while loop from flash	—	41	—	μA/MHz
		1 MHz HFRCO, CPU running while loop from flash	—	145	—	μA/MHz
Current consumption in EM1 mode with all peripherals disabled	I _{EM1}	48 MHz crystal	—	34	—	μA/MHz
		48 MHz HFRCO	—	33	TBD	μA/MHz
		32 MHz HFRCO	—	34	—	μA/MHz
		26 MHz HFRCO	—	35	TBD	μA/MHz
		16 MHz HFRCO	—	39	—	μA/MHz
		1 MHz HFRCO	—	150	TBD	μA/MHz
Current consumption in EM1 mode with all peripherals disabled and voltage scaling enabled	I _{EM1_VS}	19 MHz HFRCO	—	32	—	μA/MHz
		1 MHz HFRCO	—	136	—	μA/MHz
Current consumption in EM2 mode, with voltage scaling enabled	I _{EM2_VS}	Full 32 kB RAM retention and RTCC running from LFXO	—	1.48	—	μA
		Full 32 kB RAM retention and RTCC running from LFRCO	—	1.86	—	μA
		8 kB (1 bank) RAM retention and RTCC running from LFRCO ²	—	1.59	TBD	μA
Current consumption in EM3 mode, with voltage scaling enabled	I _{EM3_VS}	Full 32 kB RAM retention and CRYOTIMER running from ULFR-CO	—	1.23	TBD	μA

4.1.7 Wake Up Times

Table 4.9. Wake Up Times

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Wake up time from EM1	t_{EM1_WU}		—	3	—	AHB Clocks
Wake up from EM2	t_{EM2_WU}	Code execution from flash	—	10.1	—	μs
		Code execution from RAM	—	3.1	—	μs
Wake up from EM3	t_{EM3_WU}	Code execution from flash	—	10.1	—	μs
		Code execution from RAM	—	3.1	—	μs
Wake up from EM4H ¹	t_{EM4H_WU}	Executing from flash	—	88	—	μs
Wake up from EM4S ¹	t_{EM4S_WU}	Executing from flash	—	282	—	μs
Time from release of reset source to first instruction execution	t_{RESET}	Soft Pin Reset released	—	50	—	μs
		Any other reset released	—	352	—	μs
Power mode scaling time	t_{SCALE}	VSCALE0 to VSCALE2, HFCLK = 19 MHz ^{4 2}	—	31.8	—	μs
		VSCALE2 to VSCALE0, HFCLK = 19 MHz ³	—	4.3	—	μs

Note:

1. Time from wake up request until first instruction is executed. Wakeup results in device reset.
2. VSCALE0 to VSCALE2 voltage change transitions occur at a rate of 10 mV/ μs for approximately 20 μs . During this transition, peak currents will be dependent on the value of the DECOUPLE output capacitor, from 35 mA (with a 1 μF capacitor) to 70 mA (with a 2.7 μF capacitor).
3. Scaling down from VSCALE2 to VSCALE0 requires approximately 2.8 μs + 29 HFCLKs.
4. Scaling up from VSCALE0 to VSCALE2 requires approximately 30.3 μs + 28 HFCLKs.

4.1.9.2 High-Frequency Crystal Oscillator (HFXO)

Table 4.12. High-Frequency Crystal Oscillator (HFXO)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal frequency	f_{HFXO}		4	—	48	MHz
Supported crystal equivalent series resistance (ESR)	ESR_{HFXO}	48 MHz crystal	—	—	50	Ω
		24 MHz crystal	—	—	150	Ω
		4 MHz crystal	—	—	180	Ω
Supported range of crystal load capacitance ¹	$C_{\text{HFXO_CL}}$		TBD	—	TBD	pF
Nominal on-chip tuning cap range ²	$C_{\text{HFXO_T}}$	On each of HFXTAL_N and HFXTAL_P pins	8.7	—	51.7	pF
On-chip tuning capacitance step	SS_{HFXO}		—	0.08	—	pF
Startup time	t_{HFXO}	48 MHz crystal, ESR = 50 Ohm, $C_L = 8$ pF	—	350	—	μs
		24 MHz crystal, ESR = 150 Ohm, $C_L = 6$ pF	—	700	—	μs
		4 MHz crystal, ESR = 180 Ohm, $C_L = 18$ pF	—	3	—	ms
Current consumption after startup	I_{HFXO}	48 MHz crystal	—	880	—	μA
		24 MHz crystal	—	420	—	μA
		4 MHz crystal	—	80	—	μA

Note:

1. Total load capacitance as seen by the crystal.
2. The effective load capacitance seen by the crystal will be $C_{\text{HFXO_T}}/2$. This is because each XTAL pin has a tuning cap and the two caps will be seen in series by the crystal.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Frequency limits	$f_{\text{HFRCO_BAND}}$	FREQRANGE = 0, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 3, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 6, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 7, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 8, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 10, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 11, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 12, FINETUNING = 0	TBD	—	TBD	MHz
		FREQRANGE = 13, FINETUNING = 0	TBD	—	TBD	MHz

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Note: 1. ACMPVDD is a supply chosen by the setting in ACMPn_CTRL_PWRSEL and may be IOVDD, AVDD or DVDD. 2. The total ACMP current is the sum of the contributions from the ACMP and its internal voltage reference. $I_{ACMPTOTAL} = I_{ACMP} + I_{ACMPREF}$. 3. ± 100 mV differential drive. 4. In ACMPn_CTRL register. 5. In ACMPn_HYSTERESIS registers. 6. In ACMPn_INPUTSEL register.						

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Open-loop gain	G _{OL}	DRIVESTRENGTH = 3	—	135	—	dB
		DRIVESTRENGTH = 2	—	137	—	dB
		DRIVESTRENGTH = 1	—	121	—	dB
		DRIVESTRENGTH = 0	—	109	—	dB
Loop unit-gain frequency ⁷	UGF	DRIVESTRENGTH = 3, Buffer connection	—	3.38	—	MHz
		DRIVESTRENGTH = 2, Buffer connection	—	0.9	—	MHz
		DRIVESTRENGTH = 1, Buffer connection	—	132	—	kHz
		DRIVESTRENGTH = 0, Buffer connection	—	34	—	kHz
		DRIVESTRENGTH = 3, 3x Gain connection	—	2.57	—	MHz
		DRIVESTRENGTH = 2, 3x Gain connection	—	0.71	—	MHz
		DRIVESTRENGTH = 1, 3x Gain connection	—	113	—	kHz
		DRIVESTRENGTH = 0, 3x Gain connection	—	28	—	kHz
Phase margin	PM	DRIVESTRENGTH = 3, Buffer connection	—	67	—	°
		DRIVESTRENGTH = 2, Buffer connection	—	69	—	°
		DRIVESTRENGTH = 1, Buffer connection	—	63	—	°
		DRIVESTRENGTH = 0, Buffer connection	—	68	—	°
Output voltage noise	N _{OUT}	DRIVESTRENGTH = 3, Buffer connection, 10 Hz - 10 MHz	—	146	—	μVrms
		DRIVESTRENGTH = 2, Buffer connection, 10 Hz - 10 MHz	—	163	—	μVrms
		DRIVESTRENGTH = 1, Buffer connection, 10 Hz - 1 MHz	—	170	—	μVrms
		DRIVESTRENGTH = 0, Buffer connection, 10 Hz - 1 MHz	—	176	—	μVrms
		DRIVESTRENGTH = 3, 3x Gain connection, 10 Hz - 10 MHz	—	313	—	μVrms
		DRIVESTRENGTH = 2, 3x Gain connection, 10 Hz - 10 MHz	—	271	—	μVrms
		DRIVESTRENGTH = 1, 3x Gain connection, 10 Hz - 1 MHz	—	247	—	μVrms
		DRIVESTRENGTH = 0, 3x Gain connection, 10 Hz - 1 MHz	—	245	—	μVrms

4.1.19 Pulse Counter (PCNT)

Table 4.26. Pulse Counter (PCNT)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input frequency	F_{IN}	Asynchronous Single and Quadrature Modes	—	—	20	MHz
		Sampled Modes with Debounce filter set to 0.	—	—	8	kHz

4.1.20 Analog Port (APORT)

Table 4.27. Analog Port (APORT)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Supply current ^{2 1}	I_{APORT}	Operation in EM0/EM1	—	7	—	μA
		Operation in EM2/EM3	—	915	—	nA

Note:

1. Specified current is for continuous APORT operation. In applications where the APORT is not requested continuously (e.g. periodic ACMP requests from LESENSE in EM2), the average current requirements can be estimated by multiplying the duty cycle of the requests by the specified continuous current number.
2. Supply current increase that occurs when an analog peripheral requests access to APORT. This current is not included in reported module currents. Additional peripherals requesting access to APORT do not incur further current.

4.1.21 I2C

4.1.21.1 I2C Standard-mode (Sm)¹

Table 4.28. I2C Standard-mode (Sm)¹

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
SCL clock frequency ²	f _{SCL}		0	—	100	kHz
SCL clock low time	t _{LOW}		4.7	—	—	μs
SCL clock high time	t _{HIGH}		4	—	—	μs
SDA set-up time	t _{SU_DAT}		250	—	—	ns
SDA hold time ³	t _{HD_DAT}		100	—	3450	ns
Repeated START condition set-up time	t _{SU_STA}		4.7	—	—	μs
(Repeated) START condition hold time	t _{HD_STA}		4	—	—	μs
STOP condition set-up time	t _{SU_STO}		4	—	—	μs
Bus free time between a STOP and START condition	t _{BUF}		4.7	—	—	μs

Note:

1. For CLHR set to 0 in the I2Cn_CTRL register.
2. For the minimum HPPERCLK frequency required in Standard-mode, refer to the I2C chapter in the reference manual.
3. The maximum SDA hold time (t_{HD_DAT}) needs to be met only when the device does not stretch the low time of SCL (t_{LOW}).

4.1.21.3 I2C Fast-mode Plus (Fm+)¹

Table 4.30. I2C Fast-mode Plus (Fm+)¹

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
SCL clock frequency ²	f _{SCL}		0	—	1000	kHz
SCL clock low time	t _{LOW}		0.5	—	—	μs
SCL clock high time	t _{HIGH}		0.26	—	—	μs
SDA set-up time	t _{SU_DAT}		50	—	—	ns
SDA hold time	t _{HD_DAT}		100	—	—	ns
Repeated START condition set-up time	t _{SU_STA}		0.26	—	—	μs
(Repeated) START condition hold time	t _{HD_STA}		0.26	—	—	μs
STOP condition set-up time	t _{SU_STO}		0.26	—	—	μs
Bus free time between a STOP and START condition	t _{BUF}		0.5	—	—	μs

Note:

1. For CLHR set to 0 or 1 in the I2Cn_CTRL register.
2. For the minimum HPERCLK frequency required in Fast-mode Plus, refer to the I2C chapter in the reference manual.

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PC4	13	GPIO	PC5	14	GPIO
PB7	15	GPIO	PB8	16	GPIO
PA8	17	GPIO	PA9	18	GPIO
PA10	19	GPIO	RESETn	20	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.
PB11	21	GPIO	AVDD	23 27	Analog power supply.
PB13	24	GPIO	PB14	25	GPIO
PD0	28	GPIO (5V)	PD1	29	GPIO
PD2	30	GPIO (5V)	PD3	31	GPIO
PD4	32	GPIO	PD5	33	GPIO
PD6	34	GPIO	PD7	35	GPIO
PD8	36	GPIO	PC6	37	GPIO
PC7	38	GPIO	DVDD	39	Digital power supply.
DECOUPLE	40	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PC8	41	GPIO
PC9	42	GPIO	PC10	43	GPIO (5V)
PC11	44	GPIO (5V)	PC12	45	GPIO (5V)
PC13	46	GPIO (5V)	PC14	47	GPIO (5V)
PC15	48	GPIO (5V)	PF0	49	GPIO (5V)
PF1	50	GPIO (5V)	PF2	51	GPIO
PF3	52	GPIO	PF4	53	GPIO
PF5	54	GPIO	PE8	57	GPIO
PE9	58	GPIO	PE10	59	GPIO
PE11	60	GPIO	PE12	61	GPIO
PE13	62	GPIO	PE14	63	GPIO
PE15	64	GPIO			

Note:

1. GPIO with 5V tolerance are indicated by (5V).

5.7 EFM32TG11B3xx in QFN64 Device Pinout

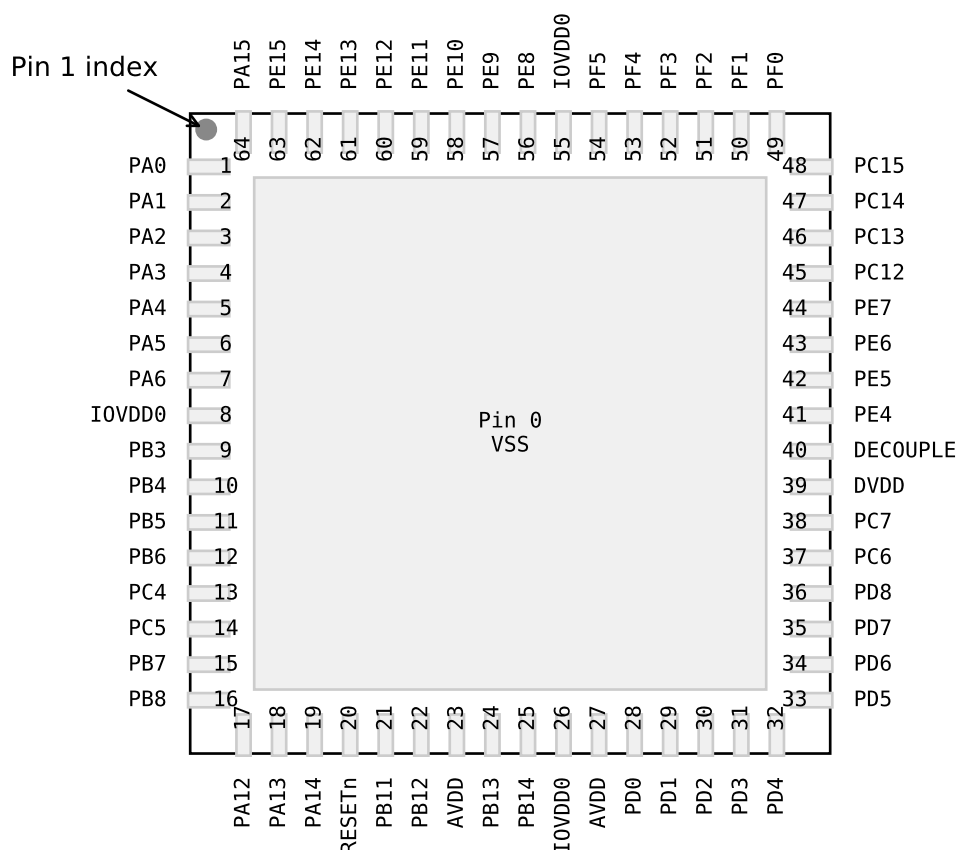


Figure 5.7. EFM32TG11B3xx in QFN64 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see [5.14 GPIO Functionality Table](#) or [5.15 Alternate Functionality Overview](#).

Table 5.7. EFM32TG11B3xx in QFN64 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
VREGVSS	0	Voltage regulator VSS	PA0	1	GPIO
PA1	2	GPIO	PA2	3	GPIO
PA3	4	GPIO	PA4	5	GPIO
PA5	6	GPIO	PA6	7	GPIO
IOVDD0	8 26 55	Digital IO power supply 0.	PB3	9	GPIO
PB4	10	GPIO	PB5	11	GPIO

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PB8	11	GPIO	PA8	12	GPIO
PA12	13	GPIO	PA14	14	GPIO
RESETn	15	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.	PB11	16	GPIO
AVDD	18 22	Analog power supply.	PB13	19	GPIO
PB14	20	GPIO	PD4	23	GPIO
PD5	24	GPIO	PD6	25	GPIO
PD7	26	GPIO	PD8	27	GPIO
VREGVSS	28	Voltage regulator VSS	VREGSW	29	DCDC regulator switching node
VREGVDD	30	Voltage regulator VDD input	DVDD	31	Digital power supply.
DECOUPLE	32	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PE4	33	GPIO
PE5	34	GPIO	PE6	35	GPIO
PE7	36	GPIO	PF0	37	GPIO (5V)
PF1	38	GPIO (5V)	PF2	39	GPIO
PF3	40	GPIO	PF4	41	GPIO
PF5	42	GPIO	PE10	45	GPIO
PE11	46	GPIO	PE12	47	GPIO
PE13	48	GPIO			

Note:

1. GPIO with 5V tolerance are indicated by (5V).

5.10 EFM32TG11B3xx in QFP48 Device Pinout

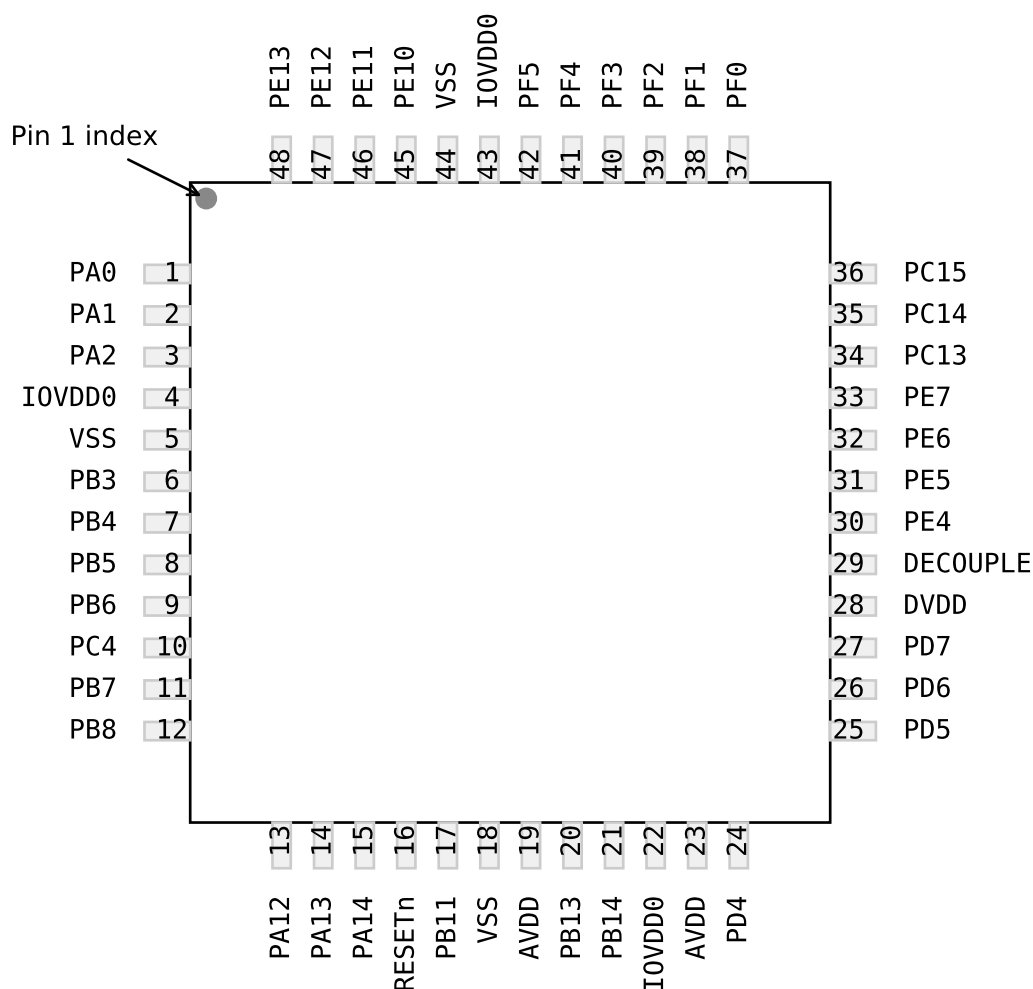


Figure 5.10. EFM32TG11B3xx in QFP48 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see [5.14 GPIO Functionality Table](#) or [5.15 Alternate Functionality Overview](#).

Table 5.10. EFM32TG11B3xx in QFP48 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PA0	1	GPIO	PA1	2	GPIO
PA2	3	GPIO	IOVDD0	4 22 43	Digital IO power supply 0.
VSS	5 18 44	Ground	PB3	6	GPIO
PB4	7	GPIO	PB5	8	GPIO
PB6	9	GPIO	PC4	10	GPIO

5.13 EFM32TG11B1xx in QFN32 Device Pinout

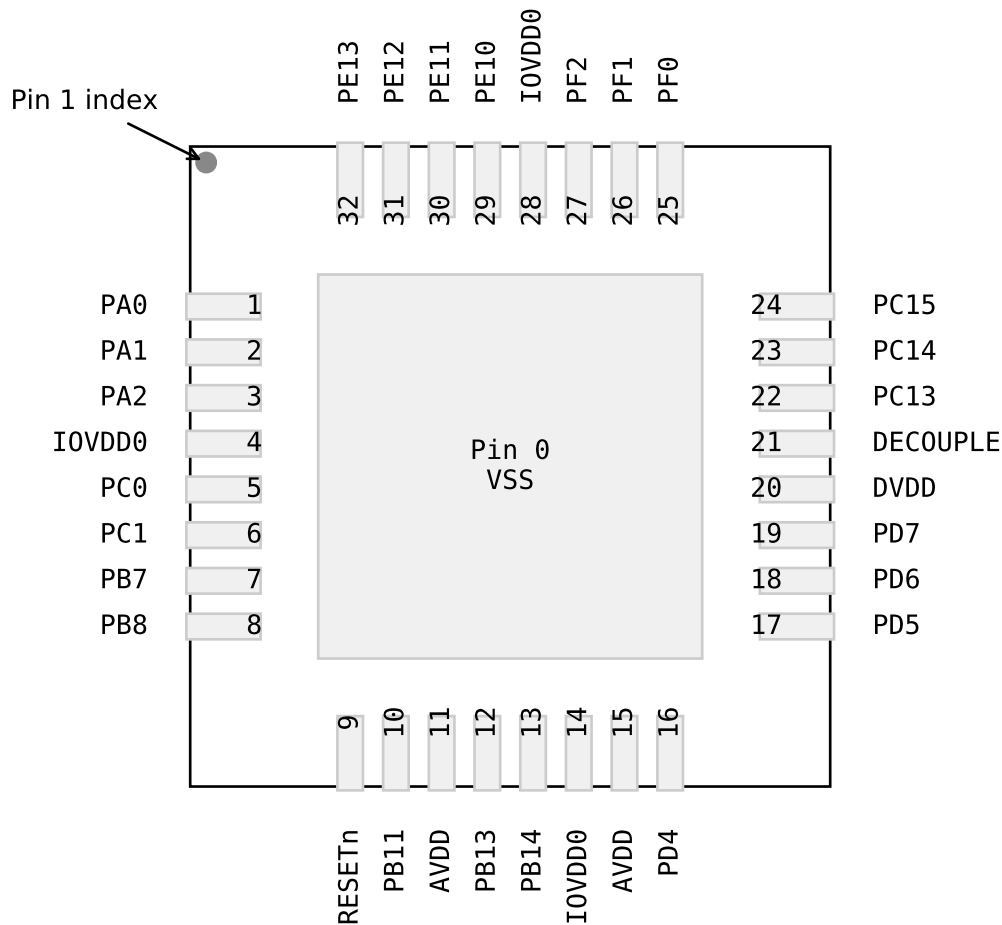


Figure 5.13. EFM32TG11B1xx in QFN32 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see [5.14 GPIO Functionality Table](#) or [5.15 Alternate Functionality Overview](#).

Table 5.13. EFM32TG11B1xx in QFN32 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
VREGVSS	0	Voltage regulator VSS	PA0	1	GPIO
PA1	2	GPIO	PA2	3	GPIO
IOVDD0	4 14 28	Digital IO power supply 0.	PC0	5	GPIO (5V)
PC1	6	GPIO (5V)	PB7	7	GPIO

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
CAN0_TX	0: PC1 1: PF2 2: PD1		CAN0 TX.
CMU_CLK0	0: PA2 1: PC12 2: PD7	4: PF2 5: PA12	Clock Management Unit, clock output number 0.
CMU_CLK1	0: PA1 1: PD8 2: PE12	4: PF3 5: PB11	Clock Management Unit, clock output number 1.
CMU_CLK2	0: PA0 1: PA3 2: PD6	4: PA3	Clock Management Unit, clock output number 2.
CMU_CLKI0	0: PD4 1: PA3 2: PB8 3: PB13	6: PE12 7: PB11	Clock Management Unit, clock input number 0.
DBG_SWCLKTCK	0: PF0		Debug-interface Serial Wire clock input and JTAG Test Clock. Note that this function is enabled to the pin out of reset, and has a built-in pull down.
DBG_SWDIOTMS	0: PF1		Debug-interface Serial Wire data input / output and JTAG Test Mode Select. Note that this function is enabled to the pin out of reset, and has a built-in pull up.
DBG_TDI	0: PF5		Debug-interface JTAG Test Data In. Note that this function becomes available after the first valid JTAG command is received, and has a built-in pull up when JTAG is active.
DBG_TDO	0: PF2		Debug-interface JTAG Test Data Out. Note that this function becomes available after the first valid JTAG command is received.
GPIO_EM4WU0	0: PA0		Pin can be used to wake the system up from EM4
GPIO_EM4WU1	0: PA6		Pin can be used to wake the system up from EM4
GPIO_EM4WU2	0: PC9		Pin can be used to wake the system up from EM4
GPIO_EM4WU3	0: PF1		Pin can be used to wake the system up from EM4

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
LCD_SEG22 / LCD_COM6	0: PB5		LCD segment line 22. This pin may also be used as LCD COM line 6
LCD_SEG23 / LCD_COM7	0: PB6		LCD segment line 23. This pin may also be used as LCD COM line 7
LCD_SEG24	0: PC4		LCD segment line 24.
LCD_SEG25	0: PC5		LCD segment line 25.
LCD_SEG26	0: PA9		LCD segment line 26.
LCD_SEG27	0: PA10		LCD segment line 27.
LCD_SEG28	0: PB11		LCD segment line 28.
LCD_SEG29	0: PB12		LCD segment line 29.
LCD_SEG30	0: PD3		LCD segment line 30.
LCD_SEG31	0: PD4		LCD segment line 31.
LCD_SEG32	0: PC6		LCD segment line 32.
LCD_SEG33	0: PC7		LCD segment line 33.
LCD_SEG34	0: PC8		LCD segment line 34.

PF7 is available on port APORT2X as CH23, the register field enumeration to connect to PF7 would be APORT2XCH23. The shared bus used by this connection is indicated in the Bus column.

Table 5.16. ACMP0 Bus and Pin Mapping

APORT4Y	APORT4X	APORT3Y	APORT3X	APORT2Y	APORT2X	APORT1Y	APORT1X	APORT0Y	APORT0X	Port
BUSDY	BUSDY	BUSDY	BUSCX	BUSBY	BUSBX	BUSAY	BUSAX	BUSACMP0Y	BUSACMP0X	Bus
				PB14			PB14			CH31
					PB13	PB13				CH30
				PB12			PB12			CH29
					PB11	PB11				CH28
										CH27
										CH26
										CH25
										CH24
										CH23
				PB6			PB6			CH22
	PF5	PF5			PB5	PB5				CH21
PF4			PF4	PB4			PB4			CH20
	PF3	PF3			PB3	PB3				CH19
PF2			PF2							CH18
	PF1	PF1								CH17
PF0			PF0							CH16
	PE15	PE15			PA15	PA15				CH15
PE14			PE14	PA14			PA14			CH14
	PE13	PE13			PA13	PA13				CH13
PE12			PE12							CH12
	PE11	PE11								CH11
PE10			PE10	PA10			PA10			CH10
	PE9	PE9			PA9	PA9				CH9
PE8			PE8							CH8
	PE7	PE7						PC7	PC7	CH7
PE6			PE6	PA6			PA6	PC6	PC6	CH6
	PE5	PE5			PA5	PA5		PC5	PC5	CH5
PE4			PE4	PA4			PA4	PC4	PC4	CH4
					PA3	PA3		PC3	PC3	CH3
				PA2			PA2	PC2	PC2	CH2
					PA1	PA1		PC1	PC1	CH1
				PA0			PA0	PC0	PC0	CH0